

Simulation of CV, TCT and CCE with an effective 2-defect model (moved to Wednesday)

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An effective 2-defect model for HPK sensors currently under investigation for the upgrade of the CMS tracker has been developed on the basis of the EVL model. With this model it is possible to describe not only the basic parameters as leakage current and depletion voltage, but also the time evolution of transient pulses as well as charge collection efficiency. The parameters for this model are discussed. A comparison between simulation and measurement data is presented.

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